

Giant spin-torque generation by heavily oxidized Pt

Hongyu An, Yusuke Kanno, Akio Asami, and Kazuya Ando*

Department of Applied Physics and Physico-Informatics, Keio University, Yokohama 223-8522, Japan



(Received 9 May 2018; revised manuscript received 28 May 2018; published 2 July 2018)

We report a giant spin-torque generation originated from the ferromagnet/heavily oxidized Pt interface. The heavily oxidized Pt was fabricated by magnetron sputtering in a mixture of oxygen and argon gases with different oxygen flow rate Q from 50% to 100%. The dominant structure of the oxidized Pt is confirmed to be PtO₂ in this Q range. We show that even in this heavily oxidized range, robust dampinglike and fieldlike spin torques can still be generated from the Ni₈₁Fe₁₉/oxidized Pt interface. By increasing the oxidation level of the oxidized Pt, the generation efficiencies of both dampinglike and fieldlike torques increase drastically, and noticeably, a maximum generation efficiency of 0.92 for the dampinglike torque is obtained. Our study further demonstrates that the generation efficiency of the dampinglike torque has a much larger value than that of the fieldlike torque, which indicates a dominant generation of the dampinglike torque from the interface. Since no energy dissipation occurs in the bulk of the spin-torque generator, this study provides a piece of information for the development of the energy-efficient spin-orbit devices based on insulating metallic oxides.

DOI: [10.1103/PhysRevB.98.014401](https://doi.org/10.1103/PhysRevB.98.014401)

I. INTRODUCTION

Spintronic devices are promising for application in future memory and logic technologies due to their high-speed response and low energy consumption [1–4]. In order to develop energy-efficient spintronic devices, the essential interest is to increase the generation efficiency of the spin-orbit torques from the charge current and to decrease the energy dissipation [5–14]. So far, topological insulators have been drawing attention as studies show their potential use as a spin-torque generator, which may significantly reduce the energy dissipation in the interior due to its bulk insulating property [15–21]. However, an ordinary insulator can also be expected to realize such purposes; nonzero spin torques can be generated in a heterostructure where a metallic magnet is sandwiched by two different insulators due to the broken inversion symmetry. In particular, metal oxides have been reported to have significant effects on the spin-torque generation. For instance, Emori *et al.* reported the sizable fieldlike torque generation from NiFe/Al₂O₃ and Cu/Al₂O₃ interfaces due to Rashba-Edelstein effects [22]. Demasius *et al.* reported a significant enhancement of the spin-torque generation by incorporating oxygen into tungsten and they interpreted that the enhancement was originated from the interface [13]. The spin-torque generation efficiency has been reported to be significantly enhanced by natural oxidation of Cu [23]. Gao *et al.* recently reported robust generation of the dampinglike torques in the SiO₂/Ni₈₁Fe₁₉/CuO_x heterostructures arising from Berry curvature at the Ni₈₁Fe₁₉/CuO_x interface [24]. Hibino *et al.* also reported an enhancement of the spin-torque generation by oxidizing the surface of the cobalt layer [25]. In our recent study, by incorporating oxygen into the widely used spintronic material, Pt, we observed a robust generation

of spin-orbit torques in metallic magnet/oxidized Pt bilayer films [26]. The interface-induced robust spin-orbit torques can switch the magnetization of the magnet even if no charge current flows in the oxidized Pt, Pt(O). The Pt(O) film was fabricated in a mixture of oxygen and argon gases by rf magnetron sputtering, in which the relative oxygen flow rate Q was varied. In the previous study, we have systematically studied the spin-torque generation in a Q range from 0 to 35%. However, for a much higher Q range, a region where Pt is heavily oxidized, the spin-torque generation is still unclear.

In this work, we study the spin-torque generation by heavily oxidized Pt: Pt(O). Pt(O) was fabricated in a Q range from 50% to 100%. The dominant structure of Pt(O) in this range of Q is confirmed to be PtO₂. By conducting spin-orbit torque ferromagnetic resonance (ST-FMR) measurement, we show that compared with our previous study in the Q range from 0 to 35%, both dampinglike and fieldlike torque generation efficiencies have been enhanced by a maximum of two times. Furthermore, we found that the spin-orbit torque generation efficiency of Pt(O) is nearly an order of magnitude larger than that of Pt.

II. EXPERIMENTAL METHODS

The films were deposited on thermally oxidized Si substrates (SiO₂) by rf magnetron sputtering at room temperature. First, the Pt(O) layer was deposited on the SiO₂ substrate in a mixture of oxygen and argon gases with a total flow of 10 standard cubic centimeters per minute. For the deposition, oxygen and argon gases were introduced into the chamber, and the amount of oxygen gas in the mixture, Q , was varied from 50% to 100% to change the oxidation level of the Pt(O) films. Then, a 5-nm-thick Ni₈₁Fe₁₉ and a 4-nm-thick SiO₂ capping layer film were deposited by applying pure argon gas. The film thickness was controlled by the deposition time with a precalibrated deposition rate. For the fabrication of the devices used in the

*ando@appi.keio.ac.jp

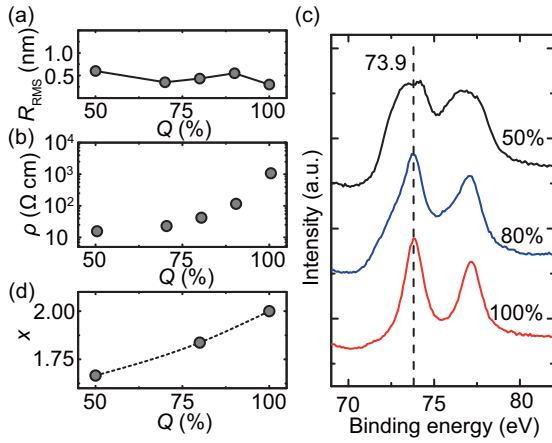


FIG. 1. (a) The surface roughness, (b) the resistivity, and (c) the XPS spectra of Pt(O) single-layer films with different Q . The binding energy of the Pt 4f peak at 73.9 eV in (b) indicates the existence of PtO₂ in Pt(O) films. (d) The oxygen stoichiometry $x = \text{O}/\text{Pt}$ with different Q in the Pt(O) films obtained from the XPS spectra. The dashed line is a guide for the eyes.

ST-FMR experiment, the substrates were patterned into a $16 \mu\text{m} \times 40 \mu\text{m}$ rectangular shape by photolithography before the deposition, and lift-off technique was used to remove the remaining part of the films after the deposition. Blanket Pt(O) single-layer films were used for the surface roughness measurement by atomic force microscopy (AFM) and the composition confirmation by x-ray photoelectron spectroscopy (XPS). All the measurements were conducted at room temperature.

III. RESULTS AND DISCUSSION

A deposition sequence of the SiO₂ capping layer/Ni₈₁Fe₁₉/Pt(O)/substrate was followed to avoid the oxidation of the Ni₈₁Fe₁₉ during the deposition. Since the Pt(O) layer was deposited in a range of high Q , the surface roughness of the Pt(O) layer may influence the spin-torque generation in the Ni₈₁Fe₁₉/Pt(O) bilayer films with different oxidation levels. Therefore, we first measured the surface roughness of Pt(O) single-layer films by AFM. As shown in Fig. 1(a), the surface root-mean-square roughness R_{RMS} in all the films with different Q are lower than 1 nm, indicating a smooth surface morphology of the Pt(O) films in the range of Q from 50% to 100%. Figure 1(b) shows the resistivity of the Pt(O) films, which increases with Q monotonically. The resistivity of Pt(O) films in this Q range (larger than $2.2 \times 10^7 \mu\Omega \text{ cm}$) is much larger than that of Ni₈₁Fe₁₉ ($106 \mu\Omega \text{ cm}$). Therefore, the charge current flows in the Pt(O) layer can be neglected in the case of the Ni₈₁Fe₁₉/Pt(O) bilayer structure for the ST-FMR measurement. In order to investigate the composition of the Pt(O) films, the XPS measurement was conducted and the Pt 4f spectra were plotted in Fig. 1(c). A previous study on Pt(O) shows that binding energies of the Pt 4f peak for Pt⁰, Pt²⁺, and Pt⁴⁺ are around 71.3, 72.3, and 74.0 eV, respectively [27]. Thus, the peak of the initial Pt 4f spectrum at 73.9 eV in Fig. 1(c) indicates the formation of PtO₂ in the Pt(O) films. It is noticeable that by increasing Q from 50% to 100%, the

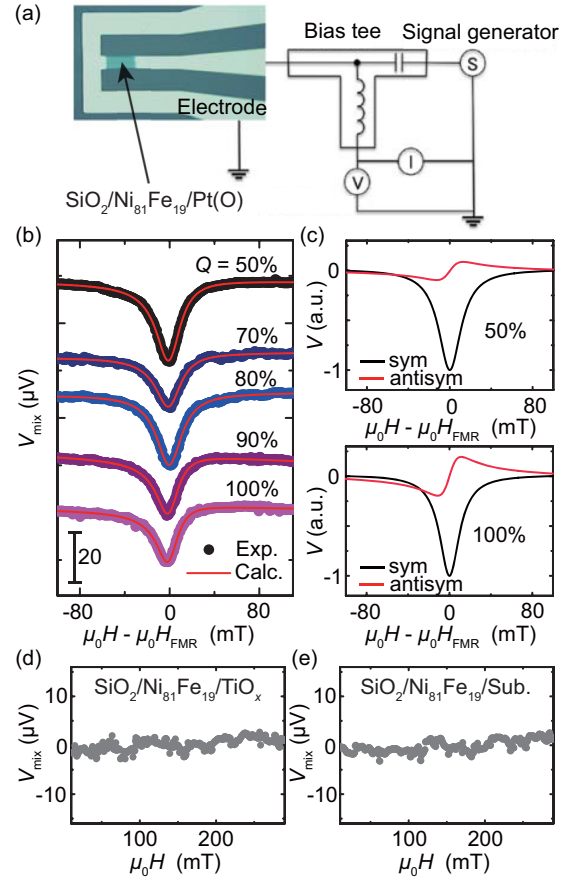


FIG. 2. (a) Schematic of the setup for ST-FMR measurement. (b) ST-FMR spectra for the SiO₂/Ni₈₁Fe₁₉/Pt(O) devices measured at 6 GHz by changing Q from 50% to 100%. The rf power of 24.7 dBm was applied for all the measurements. (c) The symmetric and antisymmetric components for $Q = 50\%$ and 100% . The symmetric component S was normalized and the antisymmetric component A divided by S was replotted for better comparison. (d) ST-FMR spectrum for the SiO₂/Ni₈₁Fe₁₉/TiO_x device measured at 6 GHz. (e) ST-FMR spectrum for the SiO₂/Ni₈₁Fe₁₉/Sub. device measured at 6 GHz.

full width half maximum of the spectra decreases. This is due to the existence of a minor portion of PtO in the Pt(O) film with $Q = 50\%$, which further reduces by increasing Q above 50% [27]. By fitting the XPS spectra, the oxygen stoichiometry $x = \text{O}/\text{Pt}$ with different Q was obtained as shown in Fig. 1(d).

Figure 2(a) shows the schematic of the setup for the ST-FMR measurement. An rf charge current was applied along the longitudinal direction, and an in-plane external magnetic field \mathbf{H} with an angle of 45° from the longitudinal direction of the device was applied. Since compared with Ni₈₁Fe₁₉, Pt(O) can be treated as a current-insulating layer, in the Ni₈₁Fe₁₉/Pt(O) bilayer structure, the rf current only generates dampinglike torque and fieldlike torque to drive magnetization precession in the Ni₈₁Fe₁₉ layer, and no Oersted field can be generated by the Pt(O) layer. The magnetization precession results in an oscillation of the resistance due to the anisotropic magnetoresistance in the Ni₈₁Fe₁₉ layer, which can be measured by using a bias tee.

The measured mixing dc voltage V_{mix} is expressed as [28–32]

$$V_{\text{mix}} = S \frac{W^2}{(\mu_0 H - \mu_0 H_{\text{FMR}})^2 + W^2} + A \frac{W(\mu_0 H - \mu_0 H_{\text{FMR}})}{(\mu_0 H - \mu_0 H_{\text{FMR}})^2 + W^2}, \quad (1)$$

where W and H_{FMR} are the spectral width and the FMR field, respectively. Here, S is the magnitude of the symmetric component of V_{mix} and A is the peak-to-dip value of the antisymmetric component of V_{mix} . In the ST-FMR signal, the symmetric component S is proportional to the dampinglike spin-orbit effective field H_{DL} [30,31]:

$$S = \frac{I_{\text{rf}} \Delta R}{2\sqrt{2}} \mu_0 H_{\text{DL}} A_{\text{sym}}, \quad (2)$$

where

$$A_{\text{sym}} = \frac{\mu_0 H_{\text{FMR}} + \mu_0 M_s}{W(2\mu_0 H_{\text{FMR}} + \mu_0 M_s)} \sqrt{\frac{\mu_0 H_{\text{FMR}}}{\mu_0 H_{\text{FMR}} + \mu_0 M_s}}. \quad (3)$$

Here, I_{rf} and ΔR are the rf current flowing in the bilayer and the resistance change of the bilayer due to the anisotropic magnetoresistance, respectively. M_s is the saturation magnetization of the $\text{Ni}_{81}\text{Fe}_{19}$ layer. Since in the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt}(\text{O})$ bilayer the Oersted field due to the current flow in the $\text{Pt}(\text{O})$ is negligible, the antisymmetric component A is proportional to the fieldlike spin-orbit effective field H_{FL} [30,31]:

$$A = \frac{I_{\text{rf}} \Delta R}{2\sqrt{2}} \mu_0 H_{\text{FL}} A_{\text{asy}}, \quad (4)$$

where

$$A_{\text{asy}} = \frac{\mu_0 H_{\text{FMR}} + \mu_0 M_s}{W(2\mu_0 H_{\text{FMR}} + \mu_0 M_s)}. \quad (5)$$

Therefore, the relative magnitude of the fieldlike effective field H_{FL} to the dampinglike effective field H_{DL} can be directly obtained from the A/S ratio using

$$\frac{H_{\text{FL}}}{H_{\text{DL}}} = \frac{A}{S} \left(1 + \frac{\mu_0 M_s}{\mu_0 H_{\text{FMR}}} \right)^{-1/2}. \quad (6)$$

Figure 2(b) shows the ST-FMR spectra V_{mix} for the $\text{SiO}_2/\text{Ni}_{81}\text{Fe}_{19}/\text{Pt}(\text{O})$ devices with Q from 50% to 100% at 6 GHz. As can be seen, despite the absence of the charge current in the interior of the $\text{Pt}(\text{O})$ layer, ST-FMR signals can still be clearly observed in all the devices, which is consistent with our previous study [26]. We also fabricated $\text{SiO}_2(4 \text{ nm})/\text{Ni}_{81}\text{Fe}_{19}(5 \text{ nm})/\text{TiO}_x(8 \text{ nm})$ and $\text{SiO}_2(4 \text{ nm})/\text{Ni}_{81}\text{Fe}_{19}(5 \text{ nm})/\text{Sub.}$ devices and conducted the ST-FMR experiments. As shown in Figs. 2(d) and 2(e), despite the magnetic resonance field around 106 mT for the $\text{Ni}_{81}\text{Fe}_{19}$ at 6 GHz, no signal can be observed. This result confirms that the large ST-FMR signal in Fig. 2(b) is originated from the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt}(\text{O})$ interface. In order to investigate the influence of Q on the spin-torque generation, we fitted the spectra with Eq. (1). Figures 2(c) and 2(d) exhibit A and S components separately in the case of $Q = 50\%$ and 100% . From this result, we obtained the relative magnitude of the fieldlike effective field H_{FL} to the dampinglike effective field H_{DL} , $|H_{\text{FL}}/H_{\text{DL}}| = 0.089$ and 0.21 for the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt}(\text{O})$ bilayer with $Q = 50\%$ and 100% , respectively. For a better comparison, $|H_{\text{FL}}/H_{\text{DL}}|$ is summarized in Fig. 3(a). Notably, $|H_{\text{FL}}/H_{\text{DL}}|$ increases by increasing Q .

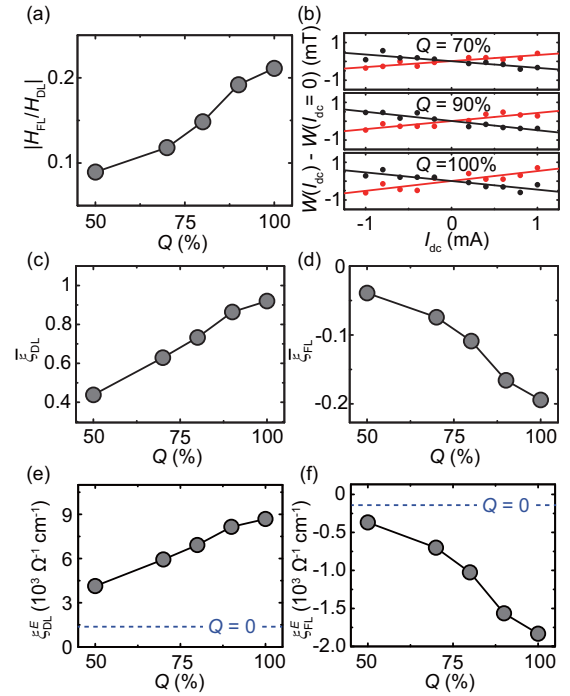


FIG. 3. (a) Q dependence of the ratio between antisymmetric component A and symmetric component S . (b) The change of the linewidth $W(I_{\text{dc}})$ of the ST-FMR spectrum as a function of the applied dc current I_{dc} for different Q . The black and red solid circles represent the linewidth change measured by applying the negative and positive field, respectively. The black and red lines are the corresponding linear fits. (c) ξ_{DL} and (d) ξ_{FL} for different Q . (e) and (f) are the corresponding dampinglike and fieldlike torque generation efficiencies per unit applied electric field E .

Next, we evaluate the dampinglike and the fieldlike torque generation efficiencies. Since no current flows in the $\text{Pt}(\text{O})$ layer, the generally used dampinglike torque efficiency ξ_{DL} and the fieldlike torque efficiency ξ_{FL} , which are defined as the generation efficiency of the spin torques from the charge current density $j_c^{\text{Pt}(\text{O})}$ flowing in the $\text{Pt}(\text{O})$ layer, cannot be calculated in the absence of $j_c^{\text{Pt}(\text{O})}$. To evaluate the generation efficiency of the dampinglike and fieldlike torques, we conducted the ST-FMR experiment by applying a dc charge current I_{dc} . The dampinglike torque generated by the dc charge current I_{dc} effectively changes the magnetic damping α of the $\text{Ni}_{81}\text{Fe}_{19}$ layer or the FMR spectral width W , as shown in Fig. 3(b), which enables the determination of the conversion efficiency from I_{dc} to the dampinglike effective field H_{DL} . Since the charge current flows only in the $\text{Ni}_{81}\text{Fe}_{19}$ layer, the damping modulation allows one to determine the generation efficiency of the dampinglike torque from the charge current density j_c^{Py} flowing in the $\text{Ni}_{81}\text{Fe}_{19}$ layer: $\xi_{\text{DL}} = \mu_0 M_s d_F H_{\text{DL}} (2e/\hbar) / j_c^{\text{Py}}$, which is different from $\xi_{\text{DL}} = \mu_0 M_s d_F H_{\text{DL}} (2e/\hbar) / j_c^{\text{Pt}(\text{O})}$. Here, the dependence of the change of the damping constant $\Delta\alpha$ on the applied dc charge current I_{dc} is expressed as [28]

$$\frac{\Delta\alpha}{I_{\text{dc}}} = \frac{\hbar}{2e \sqrt{2} M_s w d_F^2 (\mu_0 H_{\text{FMR}} + 0.5 \mu_0 M_s)} \xi_{\text{DL}}, \quad (7)$$

where d_F and w are the thickness and width of the $\text{Ni}_{81}\text{Fe}_{19}$ layer. Using Eq. (7), we determined the dampinglike torque generation efficiency $\bar{\xi}_{\text{DL}}$ as shown in Fig. 3(c). Because of $\bar{\xi}_{\text{FL}}/\bar{\xi}_{\text{DL}} = H_{\text{FL}}/H_{\text{DL}}$, the fieldlike torque generation efficiency, $\bar{\xi}_{\text{FL}} = \mu_0 M_s d_F H_{\text{FL}} (2e/\hbar) / j_c^{\text{Py}}$, can also be determined as shown in Fig. 3(d).

Figures 3(c) and 3(d) show that by increasing Q from 50% to 100%, $\bar{\xi}_{\text{DL}}$ drastically increases from 0.44 to 0.92 and $\bar{\xi}_{\text{FL}}$ increases from -0.039 to -0.19 . In order to verify whether the spin-torque generation efficiency is affected by the Pt(O) thickness, we further conducted the damping modulation experiment on a $\text{SiO}_2(4 \text{ nm})/\text{Ni}_{81}\text{Fe}_{19}(5 \text{ nm})/\text{Pt(O)}(32 \text{ nm})$ device with $Q = 50\%$, where the Pt(O) thickness is two times larger compared with the current device. $\bar{\xi}_{\text{DL}}$ and $\bar{\xi}_{\text{FL}}$ were obtained as 0.46 and -0.044 , respectively. The minor change of $\bar{\xi}_{\text{DL}}$ and $\bar{\xi}_{\text{FL}}$ confirms that the spin-torque generation is originated from the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ interface and independent of the insulating Pt(O) thickness. It is noticeable that by increasing Q , although both $\bar{\xi}_{\text{DL}}$ and $\bar{\xi}_{\text{FL}}$ increase, the former always demonstrates a much larger value than the latter. This result is contrary to the prediction of the spin torques generated by the interface Rashba effect, which suggests a dominant generation of fieldlike torque [33,34]. In the study by Emori *et al.* [22], for the $\text{NiFe}/\text{Al}_2\text{O}_3$ and $\text{Cu}/\text{Al}_2\text{O}_3$ interfaces, only the fieldlike torque due to the Rashba-Edelstein effect was observed. In contrast to these systems, we observed the sizable dampinglike torque, which is several times larger than the fieldlike torque, in the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ bilayer. Therefore, a new mechanism responsible for the dominant generation of the dampinglike torque from the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ interface is required to explain our result.

Recent theoretical and experimental studies demonstrate that the generation of the intrinsic spin-orbit torques originated from the Berry curvature at interfaces can produce sizable dampinglike components [35,36]. Furthermore, Gao *et al.* reported the observation of the dampinglike torque arising from the Berry curvature in $\text{Ni}_{81}\text{Fe}_{19}/\text{CuO}_x$ bilayer films [24]. In their study, although both dampinglike and fieldlike torques are generated from the $\text{Ni}_{81}\text{Fe}_{19}/\text{CuO}_x$ interface, the former is an order of magnitude larger than the latter despite the absence of the current flowing in the CuO_x layer, which is consistent with our result.

The semi-insulating feature of the Pt(O) layer and the large dampinglike torque generation efficiency observed in the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ bilayer provide evidence that the intrinsic Berry curvature mechanism due to the interface spin-orbit coupling is dominant in the spin-torque generation. The high electrical resistivity of the Pt(O) layer indicates that the applied charge current flows only in the $\text{Ni}_{81}\text{Fe}_{19}$ layer. In this condition, the dampinglike torque originating from the spin Hall effect in the Pt(O) layer through the spin-transfer mechanism can be neglected. Thus, only the spin-orbit coupling at the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ interface can be the source of the observed spin-orbit torque. Although recent theoretical studies predict that a sizable dampinglike torque due to the interface spin-orbit coupling can be generated by spin-dependent scattering in a ferromagnetic-metal/heavy-metal bilayer, the dampinglike torque arising from this mechanism disappears in ferromagnetic-metal/insulator bilayers [37]. This indicates that the extrinsic mechanism of the spin-orbit torque generation

does not result in the efficient generation of the dampinglike torque in the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ bilayer. Therefore, the large dampinglike torque efficiency without using the bulk charge current observed in the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ bilayer can only be explained by the intrinsic Berry curvature mechanism.

The spin-torque generation efficiency of the heavily oxidized Pt(O) is much larger than that of Pt, the most widely used heavy metal as a spin-torque source. By measuring the ST-FMR, we obtained the dampinglike and fieldlike torque generation efficiencies for a $\text{Ni}_{81}\text{Fe}_{19}(6 \text{ nm})/\text{Pt}(8 \text{ nm})$ bilayer as $\xi_{\text{DL}} = 0.044$ and $\xi_{\text{FL}} = -0.0042$, where $\xi_{\text{DL(FL)}} = \mu_0 M_s d_F H_{\text{DL(FL)}} (2e/\hbar) / j_c^{\text{Pt}}$. These values are comparable to the spin-torque generation efficiencies reported previously [28,32]. Here, the spin-torque generation efficiencies $\xi_{\text{DL(FL)}}$ for the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt}$ bilayer cannot be compared directly with $\bar{\xi}_{\text{DL(FL)}}$ for the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ bilayer. To compare the generation of the spin-orbit torques between the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt}$ and $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ bilayers, we define the spin-torque generation efficiency per unit applied electric field E [38]:

$$\xi_{\text{DL(FL)}}^E = \frac{2e}{\hbar} \mu_0 M_s d_F \frac{H_{\text{DL(FL)}}}{E}. \quad (8)$$

Here, for the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt}$ bilayer, $\xi_{\text{DL(FL)}}^E$ can be obtained using $\xi_{\text{DL(FL)}}^E = \xi_{\text{DL(FL)}} / \rho_{\text{Pt}}$: $\xi_{\text{DL}}^E = 1.4 \times 10^3 \Omega^{-1} \text{ cm}^{-1}$ and $\xi_{\text{FL}}^E = -0.13 \times 10^3 \Omega^{-1} \text{ cm}^{-1}$, where ρ_{Pt} is the resistivity of the Pt layer ($32 \mu\Omega \text{ cm}$). For the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ bilayer, using $\xi_{\text{DL(FL)}}^E = \bar{\xi}_{\text{DL(FL)}} / \rho_{\text{Py}}$, we obtained Q dependence of $\xi_{\text{DL(FL)}}^E$ as shown in Figs. 3(e) and 3(f), where ρ_{Py} is the resistivity of the $\text{Ni}_{81}\text{Fe}_{19}$ layer. As shown in Figs. 3(e) and 3(f), for the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ bilayer with $Q = 100\%$, we obtained $\xi_{\text{DL}}^E = 8.7 \times 10^3 \Omega^{-1} \text{ cm}^{-1}$ and $\xi_{\text{FL}}^E = -1.8 \times 10^3 \Omega^{-1} \text{ cm}^{-1}$, nearly an order of magnitude larger than $\xi_{\text{DL(FL)}}^E$ of Pt. In spintronics, Pt has been known as one of the most efficient spin-torque sources. This result demonstrates that the generation efficiency of the spin-orbit torque can further be enhanced by the oxidation, promising a route for exploring efficient spin-torque generators through the oxidation of heavy metals. We have also compared our result with the study by Gao *et al.* [24]. The spin-torque generation efficiency of the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ bilayer ($\xi_{\text{DL}}^E = 8.7 \times 10^3 \Omega^{-1} \text{ cm}^{-1}$) is significantly larger than that of the $\text{Ni}_{81}\text{Fe}_{19}/\text{CuO}_x$ bilayer ($\xi_{\text{DL}}^E = 20 \Omega^{-1} \text{ cm}^{-1}$), which makes the $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$ bilayer an appealing system for the application of spin orbitronics.

IV. CONCLUSIONS

In summary, we have studied the spin-torque generation by heavily oxidized Pt: Pt(O). The Pt(O) films were fabricated with different oxygen flow rate Q in a mixture of oxygen and argon gases from 50% to 100% by magnetron sputtering. The dominant structure of Pt(O) in this Q range is confirmed to be PtO_2 . By attaching a ferromagnetic layer $\text{Ni}_{81}\text{Fe}_{19}$ to the Pt(O), we show that without charge current flowing in the Pt(O) layer, robust dampinglike and fieldlike spin torques can still be generated from the interface of $\text{Ni}_{81}\text{Fe}_{19}/\text{Pt(O)}$. Further study shows that the generation efficiencies of both dampinglike and fieldlike torques increase by increasing Q . Compared with our previous study in the Q range from 0 to 35%, both dampinglike and fieldlike torque generation efficiencies have been enhanced by a maximum of two times. In particular, the dampinglike

torque generation efficiency reaches 0.92 when Q is 100%, which is much larger than the generally used heavy metals. This can drastically reduce the current density requested for the current-induced magnetization switching. Since no energy dissipation occurs in the bulk of the spin-torque generator, our study promotes the development of the energy-efficient spin-orbit devices based on insulating metallic oxides.

ACKNOWLEDGMENTS

This work was supported by JSPS KAKENHI Grants No. 26220604 and No. 26103004, the Asahi Glass Foundation, JSPS Core-to-Core Program, and Spintronics Research Network of Japan (Spin-RNJ). H.A. is JSPS International Research Fellow and acknowledges the support from the JSPS Fellowship (No. P17066 and No. 17F17066).

-
- [1] J. Sinova, S. O. Valenzuela, J. Wunderlich, C. H. Back, and T. Jungwirth, *Rev. Mod. Phys.* **87**, 1213 (2015).
- [2] T. Jungwirth, J. Wunderlich, and K. Olejnik, *Nat. Mater.* **11**, 382 (2012).
- [3] A. Manchon, H. C. Koo, J. Nitta, S. M. Frolov, and R. A. Duine, *Nat. Mater.* **14**, 871 (2015).
- [4] A. Soumyanarayanan, N. Reyren, A. Fert, and C. Panagopoulos, *Nature (London)* **539**, 509 (2016).
- [5] I. M. Miron, K. Garello, G. Gaudin, P.-J. Zermatten, M. V. Costache, S. Auffret, S. Bandiera, B. Rodmacq, A. Schuhl, and P. Gambardella, *Nature (London)* **476**, 189 (2011).
- [6] I. M. Miron, G. Gaudin, S. Auffret, B. Rodmacq, A. Schuhl, S. Pizzini, J. Vogel, and P. Gambardella, *Nat. Mater.* **9**, 230 (2010).
- [7] L. Liu, C.-F. Pai, Y. Li, H. Tseng, D. Ralph, and R. Buhrman, *Science* **336**, 555 (2012).
- [8] J. Kim, J. Sinha, M. Hayashi, M. Yamanouchi, S. Fukami, T. Suzuki, S. Mitani, and H. Ohno, *Nat. Mater.* **12**, 240 (2013).
- [9] G. Yu, P. Upadhyaya, Y. Fan, J. G. Alzate, W. Jiang, K. L. Wong, S. Takei, S. A. Bender, L.-T. Chang, Y. Jiang, M. Lang, J. Tang, Y. Wang, Y. Tserkovnyak, P. K. Amiri, and K. L. Wang, *Nat. Nanotechnol.* **9**, 548 (2014).
- [10] X. Wang, C. O. Pauyac, and A. Manchon, *Phys. Rev. B* **89**, 054405 (2014).
- [11] K. Garello, I. M. Miron, C. O. Avci, F. Freimuth, Y. Mokrousov, S. Blügel, S. Auffret, O. Boulle, G. Gaudin, and P. Gambardella, *Nat. Nanotechnol.* **8**, 587 (2013).
- [12] X. Fan, J. Wu, Y. Chen, M. J. Jerry, H. Zhang, and J. Q. Xiao, *Nat. Commun.* **4**, 1799 (2013).
- [13] K.-U. Demasius, T. Phung, W. Zhang, B. P. Hughes, S.-H. Yang, A. Kellock, W. Han, A. Pushp, and S. S. Parkin, *Nat. Commun.* **7**, 10644 (2016).
- [14] M. Akyol, J. G. Alzate, G. Yu, P. Upadhyaya, K. L. Wong, A. Ekicibil, P. K. Amiri, and K. L. Wang, *Appl. Phys. Lett.* **106**, 032406 (2015).
- [15] A. Mellnik, J. Lee, A. Richardella, J. Grab, P. Mintun, M. Fischer, A. Vaezi, A. Manchon, E.-A. Kim, N. Samarth, and D. C. Ralph, *Nature (London)* **511**, 449 (2014).
- [16] Y. Fan, P. Upadhyaya, X. Kou, M. Lang, S. Takei, Z. Wang, J. Tang, L. He, L.-T. Chang, M. Montazeri, G. Yu, W. Jiang, T. Nie, R. N. Schwartz, Y. Tserkovnyak, and K. L. Wang, *Nat. Mater.* **13**, 699 (2014).
- [17] Y. Fan, X. Kou, P. Upadhyaya, Q. Shao, L. Pan, M. Lang, X. Che, J. Tang, M. Montazeri, K. Murata, L.-T. Chang, M. Akyol, G. Yu, T. Nie, K. L. Wong, J. Liu, Y. Wang, Y. Tserkovnyak, and K. L. Wang, *Nat. Nanotechnol.* **11**, 352 (2016).
- [18] K. Kondou, R. Yoshimi, A. Tsukazaki, Y. Fukuma, J. Matsuno, K. Takahashi, M. Kawasaki, Y. Tokura, and Y. Otani, *Nat. Phys.* **12**, 1027 (2016).
- [19] J. Han, A. Richardella, S. A. Siddiqui, J. Finley, N. Samarth, and L. Liu, *Phys. Rev. Lett.* **119**, 077702 (2017).
- [20] Y. Wang, D. Zhu, Y. Wu, Y. Yang, J. Yu, R. Ramaswamy, R. Mishra, S. Shi, M. Elyasi, K.-L. Teo, Y. Wu, and H. Yang, *Nat. Commun.* **8**, 1364 (2017).
- [21] S. Shi, A. Wang, Y. Wang, R. Ramaswamy, L. Shen, J. Moon, D. Zhu, J. Yu, S. Oh, Y. Feng, and H. Yang, *Phys. Rev. B* **97**, 041115 (2018).
- [22] S. Emori, T. Nan, A. M. Belkessam, X. Wang, A. D. Matyushov, C. J. Babroski, Y. Gao, H. Lin, and N. X. Sun, *Phys. Rev. B* **93**, 180402 (2016).
- [23] H. An, Y. Kageyama, Y. Kanno, N. Enishi, and K. Ando, *Nat. Commun.* **7**, 13069 (2016).
- [24] T. Gao, A. Qaiumzadeh, H. An, A. Musha, Y. Kageyama, J. Shi, and K. Ando, [arXiv:1802.01285](https://arxiv.org/abs/1802.01285).
- [25] Y. Hibino, T. Hirai, K. Hasegawa, T. Koyama, and D. Chiba, *Appl. Phys. Lett.* **111**, 132404 (2017).
- [26] H. An, T. Ohno, Y. Kanno, Y. Kageyama, Y. Monnai, H. Maki, J. Shi, and K. Ando, *Sci. Adv.* **4**, aar2250 (2018).
- [27] D. Svintsitskiy, L. Kibis, A. Stadnichenko, S. Koscheev, V. Zaikovskii, and A. Boronin, *Chem. Phys. Chem.* **16**, 3318 (2015).
- [28] L. Liu, T. Moriyama, D. C. Ralph, and R. A. Buhrman, *Phys. Rev. Lett.* **106**, 036601 (2011).
- [29] W. Zhang, W. Han, X. Jiang, S.-H. Yang, and S. S. Parkin, *Nat. Phys.* **11**, 496 (2015).
- [30] V. Tshitoyan, C. Ciccirelli, A. P. Mihai, M. Ali, A. C. Irvine, T. A. Moore, T. Jungwirth, and A. J. Ferguson, *Phys. Rev. B* **92**, 214406 (2015).
- [31] D. Fang, H. Kurebayashi, J. Wunderlich, K. Výborný, L. Zârbo, R. Campion, A. Casiraghi, B. Gallagher, T. Jungwirth, and A. Ferguson, *Nat. Nanotechnol.* **6**, 413 (2011).
- [32] C.-F. Pai, Y. Ou, L. H. Vilela-Leão, D. C. Ralph, and R. A. Buhrman, *Phys. Rev. B* **92**, 064426 (2015).
- [33] P. M. Haney, H.-W. Lee, K.-J. Lee, A. Manchon, and M. D. Stiles, *Phys. Rev. B* **87**, 174411 (2013).
- [34] D. A. Pesin and A. H. MacDonald, *Phys. Rev. B* **86**, 014416 (2012).
- [35] H. Kurebayashi, J. Sinova, D. Fang, A. C. Irvine, T. D. Skinner, J. Wunderlich, V. Novák, R. P. Campion, B. L. Gallagher, E. K. Vehstedt, L. P. Zârbo, K. Výborný, A. J. Ferguson, and T. Jungwirth, *Nat. Nanotechnol.* **9**, 211 (2014).
- [36] H. Li, H. Gao, L. P. Zârbo, K. Výborný, X. Wang, I. Garate, F. Doğan, A. Čejchan, J. Sinova, T. Jungwirth, and A. Manchon, *Phys. Rev. B* **91**, 134402 (2015).
- [37] K.-W. Kim, K.-J. Lee, J. Sinova, H.-W. Lee, and M. D. Stiles, *Phys. Rev. B* **96**, 104438 (2017).
- [38] M.-H. Nguyen, D. C. Ralph, and R. A. Buhrman, *Phys. Rev. Lett.* **116**, 126601 (2016).